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Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

| Details | |
|--------------------------------|--|
| Product Status | Obsolete |
| Number of LABs/CLBs | 158500 |
| Number of Logic Elements/Cells | 420000 |
| Total RAM Bits | 37888000 |
| Number of I/O | 696 |
| Number of Gates | - |
| Voltage - Supply | 0.87V ~ 0.93V |
| Mounting Type | Surface Mount |
| Operating Temperature | -40°C ~ 100°C (TJ) |
| Package / Case | 1517-BBGA, FCBGA |
| Supplier Device Package | 1517-FBGA (40x40) |
| Purchase URL | https://www.e-xfl.com/product-detail/intel/5sgxea4k2f40i2n |

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Table 3. Absolute Maximum Ratings for Stratix V Devices (Part 2 of 2)

| Symbol | Description | Minimum | Maximum | Unit |
|-----------------------|--------------------------------|---------|---------|------|
| V _{CCD_FPLL} | PLL digital power supply | -0.5 | 1.8 | V |
| V _{CCA_FPLL} | PLL analog power supply | -0.5 | 3.4 | V |
| V _I | DC input voltage | -0.5 | 3.8 | V |
| T _J | Operating junction temperature | -55 | 125 | °C |
| T _{STG} | Storage temperature (No bias) | -65 | 150 | °C |
| I _{OUT} | DC output current per pin | -25 | 40 | mA |

Table 4 lists the absolute conditions for the transceiver power supply for Stratix V GX, GS, and GT devices.

Table 4. Transceiver Power Supply Absolute Conditions for Stratix V GX, GS, and GT Devices

| Symbol | Description | Devices | Minimum | Maximum | Unit |
|-----------------------|--|------------|---------|---------|------|
| V _{CCA_GXBL} | Transceiver channel PLL power supply (left side) | GX, GS, GT | -0.5 | 3.75 | V |
| V _{CCA_GXBR} | Transceiver channel PLL power supply (right side) | GX, GS | -0.5 | 3.75 | V |
| V _{CCA_GTBR} | Transceiver channel PLL power supply (right side) | GT | -0.5 | 3.75 | V |
| V _{CCHIP_L} | Transceiver hard IP power supply (left side) | GX, GS, GT | -0.5 | 1.35 | V |
| V _{CCHIP_R} | Transceiver hard IP power supply (right side) | GX, GS, GT | -0.5 | 1.35 | V |
| V _{CCHSSI_L} | Transceiver PCS power supply (left side) | GX, GS, GT | -0.5 | 1.35 | V |
| V _{CCHSSI_R} | Transceiver PCS power supply (right side) | GX, GS, GT | -0.5 | 1.35 | V |
| V _{CCR_GXBL} | Receiver analog power supply (left side) | GX, GS, GT | -0.5 | 1.35 | V |
| V _{CCR_GXBR} | Receiver analog power supply (right side) | GX, GS, GT | -0.5 | 1.35 | V |
| V _{CCR_GTBR} | Receiver analog power supply for GT channels (right side) | GT | -0.5 | 1.35 | V |
| V _{CCT_GXBL} | Transmitter analog power supply (left side) | GX, GS, GT | -0.5 | 1.35 | V |
| V _{CCT_GXBR} | Transmitter analog power supply (right side) | GX, GS, GT | -0.5 | 1.35 | V |
| V _{CCT_GTBR} | Transmitter analog power supply for GT channels (right side) | GT | -0.5 | 1.35 | V |
| V _{CCL_GTBR} | Transmitter clock network power supply (right side) | GT | -0.5 | 1.35 | V |
| V _{CCH_GXBL} | Transmitter output buffer power supply (left side) | GX, GS, GT | -0.5 | 1.8 | V |
| V _{CCH_GXBR} | Transmitter output buffer power supply (right side) | GX, GS, GT | -0.5 | 1.8 | V |

Maximum Allowed Overshoot and Undershoot Voltage

During transitions, input signals may overshoot to the voltage shown in Table 5 and undershoot to -2.0 V for input currents less than 100 mA and periods shorter than 20 ns.

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Recommended Operating Conditions

This section lists the functional operating limits for the AC and DC parameters for Stratix V devices. Table 6 lists the steady-state voltage and current values expected from Stratix V devices. Power supply ramps must all be strictly monotonic, without plateaus.

Table 6. Recommended Operating Conditions for Stratix V Devices (Part 1 of 2)

| Symbol | Description | Condition | Min ⁽⁴⁾ | Тур | Max ⁽⁴⁾ | Unit |
|----------------------------------|--|------------|--------------------|------|--------------------|------|
| | Core voltage and periphery circuitry power supply (C1, C2, I2, and I3YY speed grades) | _ | 0.87 | 0.9 | 0.93 | V |
| V _{CC} | Core voltage and periphery circuitry power supply (C2L, C3, C4, I2L, I3, I3L, and I4 speed grades) (3) | _ | 0.82 | 0.85 | 0.88 | V |
| V _{CCPT} | Power supply for programmable power technology | _ | 1.45 | 1.50 | 1.55 | V |
| V _{CC_AUX} | Auxiliary supply for the programmable power technology | _ | 2.375 | 2.5 | 2.625 | V |
| V (1) | I/O pre-driver (3.0 V) power supply | | 2.85 | 3.0 | 3.15 | V |
| V _{CCPD} ⁽¹⁾ | I/O pre-driver (2.5 V) power supply | | 2.375 | 2.5 | 2.625 | V |
| | I/O buffers (3.0 V) power supply | _ | 2.85 | 3.0 | 3.15 | ٧ |
| | I/O buffers (2.5 V) power supply | _ | 2.375 | 2.5 | 2.625 | V |
| | I/O buffers (1.8 V) power supply | _ | 1.71 | 1.8 | 1.89 | ٧ |
| V_{CCIO} | I/O buffers (1.5 V) power supply | _ | 1.425 | 1.5 | 1.575 | V |
| | I/O buffers (1.35 V) power supply | | 1.283 | 1.35 | 1.45 | V |
| | I/O buffers (1.25 V) power supply | | 1.19 | 1.25 | 1.31 | V |
| | I/O buffers (1.2 V) power supply | _ | 1.14 | 1.2 | 1.26 | V |
| | Configuration pins (3.0 V) power supply | | 2.85 | 3.0 | 3.15 | V |
| V_{CCPGM} | Configuration pins (2.5 V) power supply | _ | 2.375 | 2.5 | 2.625 | V |
| | Configuration pins (1.8 V) power supply | _ | 1.71 | 1.8 | 1.89 | V |
| V _{CCA_FPLL} | PLL analog voltage regulator power supply | | 2.375 | 2.5 | 2.625 | V |
| V _{CCD_FPLL} | PLL digital voltage regulator power supply | | 1.45 | 1.5 | 1.55 | V |
| V _{CCBAT} (2) | Battery back-up power supply (For design security volatile key register) | _ | 1.2 | _ | 3.0 | V |
| V _I | DC input voltage | _ | -0.5 | _ | 3.6 | V |
| V ₀ | Output voltage | _ | 0 | _ | V _{CCIO} | V |
| т. | Operating junction temperature | Commercial | 0 | _ | 85 | °C |
| T _J | Operating junction temperature | Industrial | -40 | _ | 100 | °C |

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Table 8 shows the transceiver power supply voltage requirements for various conditions.

Table 8. Transceiver Power Supply Voltage Requirements

| Conditions | Core Speed Grade | VCCR_GXB & VCCT_GXB (2) | VCCA_GXB | VCCH_GXB | Unit |
|--|-----------------------------------|-------------------------|----------|----------|------|
| If BOTH of the following conditions are true: | | | | | |
| ■ Data rate > 10.3 Gbps. | All | 1.05 | | | |
| ■ DFE is used. | | | | | |
| If ANY of the following conditions are true ⁽¹⁾ : | | | 3.0 | | |
| ATX PLL is used. | | | | | |
| ■ Data rate > 6.5Gbps. | All | 1.0 | | | |
| ■ DFE (data rate ≤ 10.3 Gbps), AEQ, or EyeQ feature is used. | | | | 1.5 | V |
| If ALL of the following | C1, C2, I2, and I3YY | 0.90 | 2.5 | | |
| conditions are true: ATX PLL is not used. | | | | | |
| ■ Data rate ≤ 6.5Gbps. | C2L, C3, C4, I2L, I3, I3L, and I4 | 0.85 | 2.5 | | |
| DFE, AEQ, and EyeQ are not used. | | | | | |

Notes to Table 8:

- (1) Choose this power supply voltage requirement option if you plan to upgrade your design later with any of the listed conditions.
- (2) If the VCCR_GXB and VCCT_GXB supplies are set to 1.0 V or 1.05 V, they cannot be shared with the VCC core supply. If the VCCR_GXB and VCCT_GXB are set to either 0.90 V or 0.85 V, they can be shared with the VCC core supply.

DC Characteristics

This section lists the supply current, I/O pin leakage current, input pin capacitance, on-chip termination tolerance, and hot socketing specifications.

Supply Current

Supply current is the current drawn from the respective power rails used for power budgeting. Use the Excel-based Early Power Estimator (EPE) to get supply current estimates for your design because these currents vary greatly with the resources you use.

For more information about power estimation tools, refer to the *PowerPlay Early Power Estimator User Guide* and the *PowerPlay Power Analysis* chapter in the *Quartus II Handbook*.

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Table 11. OCT Calibration Accuracy Specifications for Stratix V Devices (1) (Part 2 of 2)

| | | | | Calibratio | n Accuracy | | |
|--|--|--|------------|------------|----------------|------------|------|
| Symbol | Description | Conditions | C1 | C2,I2 | C3,I3, I3YY | C4,I4 | Unit |
| 50-Ω R _S | Internal series termination with calibration (50- Ω setting) | V _{CCIO} = 3.0, 2.5, 1.8, 1.5, 1.2 V | ±15 | ±15 | ±15 | ±15 | % |
| $34\text{-}\Omega$ and $40\text{-}\Omega$ R_S | Internal series termination with calibration (34- Ω and 40- Ω setting) | V _{CCIO} = 1.5, 1.35, 1.25, 1.2 V | ±15 | ±15 | ±15 | ±15 | % |
| 48 - Ω , 60 - Ω , 80 - Ω , and 240 - Ω R _S | Internal series termination with calibration (48- Ω , 60- Ω , 80- Ω , and 240- Ω setting) | V _{CCIO} = 1.2 V | ±15 | ±15 | ±15 | ±15 | % |
| 50-Ω R _T | Internal parallel termination with calibration (50-Ω setting) | V _{CCIO} = 2.5, 1.8, 1.5, 1.2 V | -10 to +40 | -10 to +40 | -10 to +40 | -10 to +40 | % |
| $\begin{array}{c} 20\text{-}\Omega,30\text{-}\Omega,\\ 40\text{-}\Omega,60\text{-}\Omega,\\ \text{and}\\ 120\text{-}\OmegaR_T \end{array}$ | Internal parallel termination with calibration (20- Ω , 30- Ω , 40- Ω , 60- Ω , and 120- Ω setting) | V _{CCIO} = 1.5, 1.35, 1.25 V | -10 to +40 | -10 to +40 | -10 to +40 | -10 to +40 | % |
| 60- Ω and 120- Ω R _T | Internal parallel termination with calibration (60- Ω and 120- Ω setting) | V _{CCIO} = 1.2 | -10 to +40 | -10 to +40 | -10 to +40 | -10 to +40 | % |
| $\begin{array}{c} \textbf{25-}\Omega \\ \textbf{R}_{S_left_shift} \end{array}$ | Internal left shift series termination with calibration (25- Ω R _{S_left_shift} setting) | V _{CCIO} = 3.0, 2.5, 1.8, 1.5, 1.2 V | ±15 | ±15 | ±15 | ±15 | % |

Note to Table 11:

Table 12 lists the Stratix V OCT without calibration resistance tolerance to PVT changes.

Table 12. OCT Without Calibration Resistance Tolerance Specifications for Stratix V Devices (Part 1 of 2)

| | | | Resistance Tolerance | | | | |
|-----------------------------|--|-----------------------------------|----------------------|-------|------------------|-----|------|
| Symbol | Description | Conditions | C1 | C2,I2 | 2 C3, I3, C4, I4 | | Unit |
| 25-Ω R, 50-Ω R _S | Internal series termination without calibration (25- Ω setting) | V _{CCIO} = 3.0 and 2.5 V | ±30 | ±30 | ±40 | ±40 | % |
| 25-Ω R _S | Internal series termination without calibration (25- Ω setting) | V _{CCIO} = 1.8 and 1.5 V | ±30 | ±30 | ±40 | ±40 | % |
| 25-Ω R _S | Internal series termination without calibration (25- Ω setting) | V _{CCIO} = 1.2 V | ±35 | ±35 | ±50 | ±50 | % |

⁽¹⁾ OCT calibration accuracy is valid at the time of calibration only.

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Table 13. OCT Variation after Power-Up Calibration for Stratix V Devices (Part 2 of 2) (1)

| Symbol | Description | V _{CCIO} (V) | Typical | Unit |
|--------|--|-----------------------|---------|------|
| | | 3.0 | 0.189 | |
| | OCT variation with temperature without recalibration | 2.5 | 0.208 | |
| dR/dT | | 1.8 | 0.266 | %/°C |
| | | 1.5 | 0.273 | 1 |
| | | 1.2 | 0.317 | |

Note to Table 13:

(1) Valid for a V_{CCIO} range of $\pm 5\%$ and a temperature range of 0° to $85^\circ\text{C}.$

Pin Capacitance

Table 14 lists the Stratix V device family pin capacitance.

Table 14. Pin Capacitance for Stratix V Devices

| Symbol | Description | Value | Unit |
|--------------------|--|-------|------|
| C _{IOTB} | Input capacitance on the top and bottom I/O pins | 6 | pF |
| C _{IOLR} | Input capacitance on the left and right I/O pins | 6 | pF |
| C _{OUTFB} | Input capacitance on dual-purpose clock output and feedback pins | 6 | pF |

Hot Socketing

Table 15 lists the hot socketing specifications for Stratix V devices.

Table 15. Hot Socketing Specifications for Stratix V Devices

| Symbol | Description | Maximum |
|---------------------------|--|---------------------|
| I _{IOPIN (DC)} | DC current per I/O pin | 300 μΑ |
| I _{IOPIN (AC)} | AC current per I/O pin | 8 mA ⁽¹⁾ |
| I _{XCVR-TX (DC)} | DC current per transceiver transmitter pin | 100 mA |
| I _{XCVR-RX (DC)} | DC current per transceiver receiver pin | 50 mA |

Note to Table 15:

(1) The I/O ramp rate is 10 ns or more. For ramp rates faster than 10 ns, $|I_{IOPIN}| = C dv/dt$, in which C is the I/O pin capacitance and dv/dt is the slew rate.

Table 23. Transceiver Specifications for Stratix V GX and GS Devices (1) (Part 4 of 7)

| Symbol/ | Conditions | Tra | nsceive Grade | r Speed 1 | Trai | Transceiver Speed Grade 2 | | | Transceiver Speed Grade 3 | | |
|---|---|-----|------------------|--------------|------|------------------------------|-----|-----|------------------------------|-----|----|
| Description | | Min | Тур | Max | Min | Тур | Max | Min | Тур | Max | |
| | 85– Ω setting | _ | 85 ± 30% | _ | _ | 85 ± 30% | _ | _ | 85 ± 30% | _ | Ω |
| Differential on- | 100–Ω setting | _ | 100 ± 30% | _ | _ | 100 ± 30% | _ | _ | 100 ± 30% | _ | Ω |
| chip termination resistors (21) | 120–Ω setting | _ | 120 ± 30% | | _ | 120 ± 30% | | _ | 120 ± 30% | _ | Ω |
| | 150-Ω setting | _ | 150 ± 30% | _ | _ | 150 ± 30% | _ | _ | 150 ± 30% | _ | Ω |
| | V _{CCR_GXB} = 0.85 V or 0.9 V full bandwidth | _ | 600 | _ | _ | 600 | _ | _ | 600 | _ | mV |
| V _{ICM} (AC and DC | V _{CCR_GXB} = 0.85 V or 0.9 V half bandwidth | _ | 600 | _ | _ | 600 | _ | _ | 600 | _ | mV |
| coupled) | V _{CCR_GXB} = 1.0 V/1.05 V full bandwidth | _ | 700 | _ | _ | 700 | _ | _ | 700 | _ | mV |
| | V _{CCR_GXB} = 1.0 V half bandwidth | _ | 750 | _ | _ | 750 | _ | _ | 750 | _ | mV |
| t _{LTR} (11) | _ | _ | _ | 10 | _ | _ | 10 | _ | _ | 10 | μs |
| t _{LTD} (12) | _ | 4 | _ | | 4 | | | 4 | | _ | μs |
| t _{LTD_manual} (13) | _ | 4 | _ | | 4 | _ | | 4 | _ | | μs |
| t _{LTR_LTD_manual} (14) | _ | 15 | _ | _ | 15 | | _ | 15 | | _ | μs |
| Run Length | _ | | _ | 200 | | _ | 200 | _ | | 200 | UI |
| Programmable equalization (AC Gain) ⁽¹⁰⁾ | Full bandwidth (6.25 GHz) Half bandwidth (3.125 GHz) | _ | _ | 16 | _ | _ | 16 | _ | _ | 16 | dB |

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Table 23. Transceiver Specifications for Stratix V GX and GS Devices (1) (Part 7 of 7)

| Symbol/ Description | Conditions | | | | Transceiver Speed Grade 2 | | | Transceiver Speed Grade 3 | | | Unit |
|----------------------------|------------|-----|-----|-----|------------------------------|-----|-----|------------------------------|-----|-----|------|
| | | Min | Тур | Max | Min | Тур | Max | Min | Тур | Max | |
| t _{pll_lock} (16) | _ | | _ | 10 | _ | _ | 10 | _ | _ | 10 | μs |

Notes to Table 23:

- (1) Speed grades shown in Table 23 refer to the PMA Speed Grade in the device ordering code. The maximum data rate could be restricted by the Core/PCS speed grade. Contact your Altera Sales Representative for the maximum data rate specifications in each speed grade combination offered. For more information about device ordering codes, refer to the *Stratix V Device Overview*.
- (2) The reference clock common mode voltage is equal to the V_{CCR_GXB} power supply level.
- (3) This supply must be connected to 1.0 V if the transceiver is configured at a data rate > 6.5 Gbps, and to 1.05 V if configured at a data rate > 10.3 Gbps when DFE is used. For data rates up to 6.5 Gbps, you can connect this supply to 0.85 V.
- (4) This supply follows VCCR_GXB.
- (5) The device cannot tolerate prolonged operation at this absolute maximum.
- (6) The differential eye opening specification at the receiver input pins assumes that **Receiver Equalization** is disabled. If you enable **Receiver Equalization**, the receiver circuitry can tolerate a lower minimum eye opening, depending on the equalization level.
- (7) The Quartus II software automatically selects the appropriate slew rate depending on the configured data rate or functional mode.
- (8) The input reference clock frequency options depend on the data rate and the device speed grade.
- (9) The line data rate may be limited by PCS-FPGA interface speed grade.
- (10) Refer to Figure 1 for the GX channel AC gain curves. The total effective AC gain is the AC gain minus the DC gain.
- (11) t_{LTR} is the time required for the receive CDR to lock to the input reference clock frequency after coming out of reset.
- (12) t_{I TD} is time required for the receiver CDR to start recovering valid data after the rx_is_lockedtodata signal goes high.
- (13) t_{LTD_manual} is the time required for the receiver CDR to start recovering valid data after the rx_is_lockedtodata signal goes high when the CDR is functioning in the manual mode.
- (14) t_{LTR_LTD_manual} is the time the receiver CDR must be kept in lock to reference (LTR) mode after the rx_is_lockedtoref signal goes high when the CDR is functioning in the manual mode.
- (15) $t_{pll\ powerdown}$ is the PLL powerdown minimum pulse width.
- (16) t_{nll lock} is the time required for the transmitter CMU/ATX PLL to lock to the input reference clock frequency after coming out of reset.
- (17) To calculate the REFCLK rms phase jitter requirement for PCle at reference clock frequencies other than 100 MHz, use the following formula: REFCLK rms phase jitter at f(MHz) = REFCLK rms phase jitter at 100 MHz × 100/f.
- (18) The maximum peak to peak differential input voltage V_{ID} after device configuration is equal to 4 × (absolute V_{MAX} for receiver pin V_{ICM}).
- (19) For ES devices, R_{REF} is 2000 Ω ±1%.
- (20) To calculate the REFCLK phase noise requirement at frequencies other than 622 MHz, use the following formula: REFCLK phase noise at f(MHz) = REFCLK phase noise at 622 MHz + 20*log(f/622).
- (21) SFP/+ optical modules require the host interface to have RD+/- differentially terminated with 100 Ω. The internal OCT feature is available after the Stratix V FPGA configuration is completed. Altera recommends that FPGA configuration is completed before inserting the optical module. Otherwise, minimize unnecessary removal and insertion with unconfigured devices.
- (22) Refer to Figure 2.
- (23) For oversampling designs to support data rates less than the minimum specification, the CDR needs to be in LTR mode only.
- (24) I3YY devices can achieve data rates up to 10.3125 Gbps.
- (25) When you use fPLL as a TXPLL of the transceiver.
- (26) REFCLK performance requires to meet transmitter REFCLK phase noise specification.
- (27) Minimum eye opening of 85 mV is only for the unstressed input eye condition.

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Table 28. Transceiver Specifications for Stratix V GT Devices (Part 1 of 5) $^{(1)}$

| Symbol/ | Conditions | S | Transceive Speed Grade | | | Transceive peed Grade | | Unit | | |
|--|--|--|--|------|------|--------------------------|----------|----------|--|--|
| Description | | Min | Тур | Max | Min | Тур | Max | 5 | | |
| Reference Clock | l | | <u>I</u> | ul. | | | <u>I</u> | <u>I</u> | | |
| Supported I/O Standards | Dedicated reference clock pin | 1.2-V PCN | 1.2-V PCML, 1.4-V PCML, 1.5-V PCML, 2.5-V PCML, Differential LVPECL, L and HCSL | | | | | | | |
| otandardo | RX reference clock pin | 1.4-V PCML, 1.5-V PCML, 2.5-V PCML, LVPECL, and LVDS | | | | | | | | |
| Input Reference Clock Frequency (CMU PLL) ⁽⁶⁾ | _ | 40 | _ | 710 | 40 | _ | 710 | MHz | | |
| Input Reference Clock Frequency (ATX PLL) (6) | _ | 100 | _ | 710 | 100 | _ | 710 | MHz | | |
| Rise time | 20% to 80% | _ | _ | 400 | _ | _ | 400 | | | |
| Fall time | 80% to 20% | _ | _ | 400 | _ | <u> </u> | 400 | ps | | |
| Duty cycle | _ | 45 | _ | 55 | 45 | _ | 55 | % | | |
| Spread-spectrum modulating clock frequency | PCI Express (PCIe) | 30 | _ | 33 | 30 | _ | 33 | kHz | | |
| Spread-spectrum downspread | PCle | | 0 to -0.5 | _ | _ | 0 to -0.5 | _ | % | | |
| On-chip termination resistors (19) | _ | _ | 100 | _ | _ | 100 | _ | Ω | | |
| Absolute V _{MAX} (3) | Dedicated reference clock pin | _ | _ | 1.6 | _ | _ | 1.6 | V | | |
| | RX reference clock pin | _ | _ | 1.2 | _ | _ | 1.2 | | | |
| Absolute V _{MIN} | _ | -0.4 | _ | _ | -0.4 | | _ | V | | |
| Peak-to-peak differential input voltage | _ | 200 | _ | 1600 | 200 | _ | 1600 | mV | | |
| V _{ICM} (AC coupled) | Dedicated reference clock pin | | 1050/1000 | 2) | 1 | 050/1000 | 2) | mV | | |
| | RX reference clock pin | 1 | .0/0.9/0.85 | (22) | 1. | 0/0.9/0.85 | (22) | V | | |
| V _{ICM} (DC coupled) | HCSL I/O standard for PCIe reference clock | 250 | _ | 550 | 250 | _ | 550 | mV | | |

Figure 6 shows the Stratix V DC gain curves for GT channels.

Figure 6. DC Gain Curves for GT Channels

Transceiver Characterization

This section summarizes the Stratix V transceiver characterization results for compliance with the following protocols:

- Interlaken
- 40G (XLAUI)/100G (CAUI)
- 10GBase-KR
- QSGMII
- XAUI
- SFI
- Gigabit Ethernet (Gbe / GIGE)
- SPAUI
- Serial Rapid IO (SRIO)
- CPRI
- OBSAI
- Hyper Transport (HT)
- SATA
- SAS
- CEI

Table 31. PLL Specifications for Stratix V Devices (Part 3 of 3)

| | Symbol | Parameter | Min | Тур | Max | Unit |
|---|--------|--|--------|------|-------|------|
| f | RES | Resolution of VCO frequency (f _{INPFD} = 100 MHz) | 390625 | 5.96 | 0.023 | Hz |

Notes to Table 31:

- (1) This specification is limited in the Quartus II software by the I/O maximum frequency. The maximum I/O frequency is different for each I/O standard.
- (2) This specification is limited by the lower of the two: I/O f_{MAX} or f_{OUT} of the PLL.
- (3) A high input jitter directly affects the PLL output jitter. To have low PLL output clock jitter, you must provide a clean clock source < 120 ps.
- (4) f_{REF} is fIN/N when N = 1.
- (5) Peak-to-peak jitter with a probability level of 10⁻¹² (14 sigma, 99.9999999974404% confidence level). The output jitter specification applies to the intrinsic jitter of the PLL, when an input jitter of 30 ps is applied. The external memory interface clock output jitter specifications use a different measurement method and are available in Table 44 on page 52.
- (6) The cascaded PLL specification is only applicable with the following condition:
 - a. Upstream PLL: 0.59Mhz \le Upstream PLL BW < 1 MHz
 - b. Downstream PLL: Downstream PLL BW > 2 MHz
- (7) High bandwidth PLL settings are not supported in external feedback mode.
- (8) The external memory interface clock output jitter specifications use a different measurement method, which is available in Table 42 on page 50.
- (9) The VCO frequency reported by the Quartus II software in the PLL Usage Summary section of the compilation report takes into consideration the VCO post-scale counter K value. Therefore, if the counter K has a value of 2, the frequency reported can be lower than the f_{VCO} specification.
- (10) This specification only covers fractional PLL for low bandwidth. The f_{VCO} for fractional value range 0.05 0.95 must be \geq 1000 MHz, while f_{VCO} for fractional value range 0.20 0.80 must be \geq 1200 MHz.
- (11) This specification only covered fractional PLL for low bandwidth. The f_{VCO} for fractional value range 0.05-0.95 must be ≥ 1000 MHz.
- (12) This specification only covered fractional PLL for low bandwidth. The f_{VCO} for fractional value range 0.20-0.80 must be ≥ 1200 MHz.

DSP Block Specifications

Table 32 lists the Stratix V DSP block performance specifications.

Table 32. Block Performance Specifications for Stratix V DSP Devices (Part 1 of 2)

| | | | F | Peformano | e | | | | | | | |
|--|---------------------|---------|------------|-----------|------------------|-----|-----|------|--|--|--|--|
| Mode | C1 | C2, C2L | 12, 12L | C3 | 13, 13L, 13YY | C4 | 14 | Unit | | | | |
| | Modes using one DSP | | | | | | | | | | | |
| Three 9 x 9 | 600 | 600 | 600 | 480 | 480 | 420 | 420 | MHz | | | | |
| One 18 x 18 | 600 | 600 | 600 | 480 | 480 | 420 | 400 | MHz | | | | |
| Two partial 18 x 18 (or 16 x 16) | 600 | 600 | 600 | 480 | 480 | 420 | 400 | MHz | | | | |
| One 27 x 27 | 500 | 500 | 500 | 400 | 400 | 350 | 350 | MHz | | | | |
| One 36 x 18 | 500 | 500 | 500 | 400 | 400 | 350 | 350 | MHz | | | | |
| One sum of two 18 x 18(One sum of 2 16 x 16) | 500 | 500 | 500 | 400 | 400 | 350 | 350 | MHz | | | | |
| One sum of square | 500 | 500 | 500 | 400 | 400 | 350 | 350 | MHz | | | | |
| One 18 x 18 plus 36 (a x b) + c | 500 | 500 | 500 | 400 | 400 | 350 | 350 | MHz | | | | |
| | | Modes u | sing two I | OSPs | | | | • | | | | |
| Three 18 x 18 | 500 | 500 | 500 | 400 | 400 | 350 | 350 | MHz | | | | |
| One sum of four 18 x 18 | 475 | 475 | 475 | 380 | 380 | 300 | 300 | MHz | | | | |
| One sum of two 27 x 27 | 465 | 465 | 450 | 380 | 380 | 300 | 290 | MHz | | | | |
| One sum of two 36 x 18 | 475 | 475 | 475 | 380 | 380 | 300 | 300 | MHz | | | | |
| One complex 18 x 18 | 500 | 500 | 500 | 400 | 400 | 350 | 350 | MHz | | | | |
| One 36 x 36 | 475 | 475 | 475 | 380 | 380 | 300 | 300 | MHz | | | | |

Table 33. Memory Block Performance Specifications for Stratix V Devices (1), (2) (Part 2 of 2)

| | | Resour | ces Used | | | Pe | erforman | ce | | | |
|---------------|---|--------|----------|-----|------------|-----|----------|---------|---------------------|-----|------|
| Memory | Mode | ALUTS | Memory | C1 | C2, C2L | C3 | C4 | 12, 12L | 13, 13L, 13YY | 14 | Unit |
| | Single-port, all supported widths | 0 | 1 | 700 | 700 | 650 | 550 | 700 | 500 | 450 | MHz |
| | Simple dual-port, all supported widths | 0 | 1 | 700 | 700 | 650 | 550 | 700 | 500 | 450 | MHz |
| | Simple dual-port with the read-during-write option set to Old Data , all supported widths | 0 | 1 | 525 | 525 | 455 | 400 | 525 | 455 | 400 | MHz |
| M20K Block | Simple dual-port with ECC enabled, 512 × 32 | 0 | 1 | 450 | 450 | 400 | 350 | 450 | 400 | 350 | MHz |
| | Simple dual-port with ECC and optional pipeline registers enabled, 512 × 32 | 0 | 1 | 600 | 600 | 500 | 450 | 600 | 500 | 450 | MHz |
| | True dual port, all supported widths | 0 | 1 | 700 | 700 | 650 | 550 | 700 | 500 | 450 | MHz |
| | ROM, all supported widths | 0 | 1 | 700 | 700 | 650 | 550 | 700 | 500 | 450 | MHz |

Notes to Table 33:

Temperature Sensing Diode Specifications

Table 34 lists the internal TSD specification.

Table 34. Internal Temperature Sensing Diode Specification

| Tei | mperature Range | Accuracy | Offset Calibrated Option | Sampling Rate | Conversion Time | Resolution | Minimum Resolution with no Missing Codes |
|------|--------------------|----------|--------------------------------|----------------|--------------------|------------|---|
| -40° | °C to 100°C | ±8°C | No | 1 MHz, 500 KHz | < 100 ms | 8 bits | 8 bits |

Table 35 lists the specifications for the Stratix V external temperature sensing diode.

Table 35. External Temperature Sensing Diode Specifications for Stratix V Devices

| Description | Min | Тур | Max | Unit |
|--|-------|-------|-------|------|
| I _{bias} , diode source current | 8 | _ | 200 | μΑ |
| V _{bias,} voltage across diode | 0.3 | _ | 0.9 | V |
| Series resistance | _ | _ | <1 | Ω |
| Diode ideality factor | 1.006 | 1.008 | 1.010 | _ |

⁽¹⁾ To achieve the maximum memory block performance, use a memory block clock that comes through global clock routing from an on-chip PLL set to **50%** output duty cycle. Use the Quartus II software to report timing for this and other memory block clocking schemes.

⁽²⁾ When you use the error detection cyclical redundancy check (CRC) feature, there is no degradation in F_{MAX}.

⁽³⁾ The F_{MAX} specification is only achievable with Fitter options, **MLAB Implementation In 16-Bit Deep Mode** enabled.

Table 36. High-Speed I/O Specifications for Stratix V Devices (1), (2) (Part 4 of 4)

| Cumbal | Conditions | | C1 | | C2, | C2L, I | 2, I2L | C3, | I3, I3I | ., I3YY | C4,14 | | | Unit |
|-------------------------------|--|-----|-----|-----------|-----|--------|-----------|-----|---------|-----------|-------|-----|-----------|----------|
| Symbol | Conuntions | Min | Тур | Max | Min | Тур | Max | Min | Тур | Max | Min | Тур | Max | Ullit |
| | SERDES factor J = 3 to 10 | (6) | _ | (8) | (6) | | (8) | (6) | | (8) | (6) | _ | (8) | Mbps |
| f _{HSDR} (data rate) | SERDES factor J = 2, uses DDR Registers | (6) | | (7) | (6) | | (7) | (6) | | (7) | (6) | | (7) | Mbps |
| | SERDES factor J = 1, uses SDR Register | (6) | _ | (7) | (6) | _ | (7) | (6) | _ | (7) | (6) | _ | (7) | Mbps |
| DPA Mode | | | | | | | | | | | | | | |
| DPA run length | _ | | _ | 1000 0 | | | 1000 0 | _ | | 1000 0 | _ | _ | 1000 0 | UI |
| Soft CDR mode | • | | | | | | | | | | | | | |
| Soft-CDR PPM tolerance | _ | _ | _ | 300 | _ | _ | 300 | _ | _ | 300 | _ | _ | 300 | ± PPM |
| Non DPA Mode | , | | | | | | | | | | | | | |
| Sampling Window | _ | _ | _ | 300 | _ | | 300 | _ | | 300 | _ | _ | 300 | ps |

Notes to Table 36:

- (1) When J = 3 to 10, use the serializer/deserializer (SERDES) block.
- (2) When J = 1 or 2, bypass the SERDES block.
- (3) This only applies to DPA and soft-CDR modes.
- (4) Clock Boost Factor (W) is the ratio between the input data rate to the input clock rate.
- (5) This is achieved by using the **LVDS** clock network.
- (6) The minimum specification depends on the clock source (for example, the PLL and clock pin) and the clock routing resource (global, regional, or local) that you use. The I/O differential buffer and input register do not have a minimum toggle rate.
- (7) The maximum ideal frequency is the SERDES factor (J) x the PLL maximum output frequency (fOUT) provided you can close the design timing and the signal integrity simulation is clean.
- (8) You can estimate the achievable maximum data rate for non-DPA mode by performing link timing closure analysis. You must consider the board skew margin, transmitter delay margin, and receiver sampling margin to determine the maximum data rate supported.
- (9) If the receiver with DPA enabled and transmitter are using shared PLLs, the minimum data rate is 150 Mbps.
- (10) You must calculate the leftover timing margin in the receiver by performing link timing closure analysis. You must consider the board skew margin, transmitter channel-to-channel skew, and receiver sampling margin to determine leftover timing margin.
- (11) The F_{MAX} specification is based on the fast clock used for serial data. The interface F_{MAX} is also dependent on the parallel clock domain which is design-dependent and requires timing analysis.
- (12) Stratix V RX LVDS will need DPA. For Stratix V TX LVDS, the receiver side component must have DPA.
- (13) Stratix V LVDS serialization and de-serialization factor needs to be x4 and above.
- (14) Requires package skew compensation with PCB trace length.
- (15) Do not mix single-ended I/O buffer within LVDS I/O bank.
- (16) Chip-to-chip communication only with a maximum load of 5 pF.
- (17) When using True LVDS RX channels for emulated LVDS TX channel, only serialization factors 1 and 2 are supported.

Table 42. Memory Output Clock Jitter Specification for Stratix V Devices (1), (Part 2 of 2) (2), (3)

| Clock Network | Parameter | Symbol | C | 1 | C2, C2L | , I2 , I2L | 12, 12L C3, 13, 13L, 13YY | | C4 | Unit | |
|------------------|------------------------------|-----------------------|-------|------|---------|--------------------------|------------------------------|-----|-----|------|----|
| NEIWUIK | | | Min | Max | Min | Max | Min | Max | Min | Max | |
| | Clock period jitter | t _{JIT(per)} | -25 | 25 | -25 | 25 | -30 | 30 | -35 | 35 | ps |
| PHY Clock | Cycle-to-cycle period jitter | t _{JIT(cc)} | -50 | 50 | -50 | 50 | -60 | 60 | -70 | 70 | ps |
| | Duty cycle jitter | $t_{JIT(duty)}$ | -37.5 | 37.5 | -37.5 | 37.5 | -45 | 45 | -56 | 56 | ps |

Notes to Table 42:

- (1) The clock jitter specification applies to the memory output clock pins generated using differential signal-splitter and DDIO circuits clocked by a PLL output routed on a PHY, regional, or global clock network as specified. Altera recommends using PHY clock networks whenever possible.
- (2) The clock jitter specification applies to the memory output clock pins clocked by an integer PLL.
- (3) The memory output clock jitter is applicable when an input jitter of 30 ps peak-to-peak is applied with bit error rate (BER) -12, equivalent to 14 sigma.

OCT Calibration Block Specifications

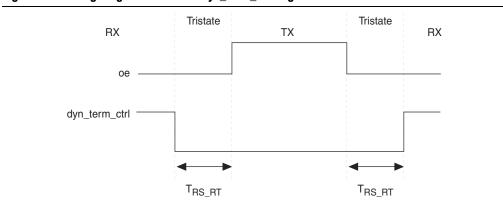
Table 43 lists the OCT calibration block specifications for Stratix V devices.

Table 43. OCT Calibration Block Specifications for Stratix V Devices

| Symbol | Description | Min | Тур | Max | Unit |
|-----------------------|--|-----|------|-----|--------|
| OCTUSRCLK | Clock required by the OCT calibration blocks | _ | _ | 20 | MHz |
| T _{OCTCAL} | Number of OCTUSRCLK clock cycles required for OCT $\ensuremath{R}_{\ensuremath{S}}/\ensuremath{R}_{\ensuremath{T}}$ calibration | | 1000 | _ | Cycles |
| T _{OCTSHIFT} | Number of OCTUSRCLK clock cycles required for the OCT code to shift out | | 32 | _ | Cycles |
| T _{RS_RT} | Time required between the $\mathtt{dyn_term_ctrl}$ and oe signal transitions in a bidirectional I/O buffer to dynamically switch between OCT R_S and R_T (Figure 10) | _ | 2.5 | _ | ns |

Figure 10 shows the timing diagram for the oe and dyn term ctrl signals.

Figure 10. Timing Diagram for oe and dyn_term_ctrl Signals



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| Table 46. | JTAG Timino | Parameters ar | nd Values | for Stratix V Devices |
|-----------|-------------|---------------|-----------|-----------------------|
|-----------|-------------|---------------|-----------|-----------------------|

| Symbol | Description | Min | Max | Unit |
|-------------------|--|-----|-------------------|------|
| t _{JPH} | JTAG port hold time | 5 | _ | ns |
| t _{JPCO} | JTAG port clock to output | _ | 11 ⁽¹⁾ | ns |
| t _{JPZX} | JTAG port high impedance to valid output | _ | 14 ⁽¹⁾ | ns |
| t _{JPXZ} | JTAG port valid output to high impedance | _ | 14 ⁽¹⁾ | ns |

Notes to Table 46:

- (1) A 1 ns adder is required for each V_{CCIO} voltage step down from 3.0 V. For example, t_{JPCO} = 12 ns if V_{CCIO} of the TDO I/O bank = 2.5 V, or 13 ns if it equals 1.8 V.
- (2) The minimum TCK clock period is 167 ns if VCCBAT is within the range 1.2V-1.5V when you perform the volatile key programming.

Raw Binary File Size

For the POR delay specification, refer to the "POR Delay Specification" section of the "Configuration, Design Security, and Remote System Upgrades in Stratix V Devices".

Table 47 lists the uncompressed raw binary file (.rbf) sizes for Stratix V devices.

Table 47. Uncompressed .rbf Sizes for Stratix V Devices

| Family | Device | Package | Configuration .rbf Size (bits) | IOCSR .rbf Size (bits) (4), (5) |
|--------------|--------|------------------------------|--------------------------------|---------------------------------|
| | ECCVAO | H35, F40, F35 ⁽²⁾ | 213,798,880 | 562,392 |
| | 5SGXA3 | H29, F35 ⁽³⁾ | 137,598,880 | 564,504 |
| | 5SGXA4 | _ | 213,798,880 | 563,672 |
| | 5SGXA5 | _ | 269,979,008 | 562,392 |
| | 5SGXA7 | _ | 269,979,008 | 562,392 |
| Stratix V GX | 5SGXA9 | _ | 342,742,976 | 700,888 |
| | 5SGXAB | _ | 342,742,976 | 700,888 |
| | 5SGXB5 | _ | 270,528,640 | 584,344 |
| | 5SGXB6 | _ | 270,528,640 | 584,344 |
| | 5SGXB9 | _ | 342,742,976 | 700,888 |
| | 5SGXBB | _ | 342,742,976 | 700,888 |
| Chrotin V CT | 5SGTC5 | _ | 269,979,008 | 562,392 |
| Stratix V GT | 5SGTC7 | _ | 269,979,008 | 562,392 |
| | 5SGSD3 | _ | 137,598,880 | 564,504 |
| | FCCCD4 | F1517 | 213,798,880 | 563,672 |
| Ctrativ V CC | 5SGSD4 | _ | 137,598,880 | 564,504 |
| Stratix V GS | 5SGSD5 | _ | 213,798,880 | 563,672 |
| | 5SGSD6 | _ | 293,441,888 | 565,528 |
| | 5SGSD8 | _ | 293,441,888 | 565,528 |

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FPP Configuration Timing when DCLK-to-DATA [] = 1

Figure 12 shows the timing waveform for FPP configuration when using a MAX II or MAX V device as an external host. This waveform shows timing when the DCLK-to-DATA[] ratio is 1.

Figure 12. FPP Configuration Timing Waveform When the DCLK-to-DATA[] Ratio is 1 (1), (2)



Notes to Figure 12:

- (1) Use this timing waveform when the DCLK-to-DATA[] ratio is 1.
- (2) The beginning of this waveform shows the device in user mode. In user mode, nCONFIG, nSTATUS, and CONF_DONE are at logic-high levels. When nCONFIG is pulled low, a reconfiguration cycle begins.
- (3) After power-up, the Stratix V device holds nSTATUS low for the time of the POR delay.
- (4) After power-up, before and during configuration, CONF DONE is low.
- (5) Do not leave DCLK floating after configuration. DCLK is ignored after configuration is complete. It can toggle high or low if required.
- (6) For FPP ×16, use DATA [15..0]. For FPP ×8, use DATA [7..0]. DATA [31..0] are available as a user I/O pin after configuration. The state of this pin depends on the dual-purpose pin settings.
- (7) To ensure a successful configuration, send the entire configuration data to the Stratix V device. CONF_DONE is released high when the Stratix V device receives all the configuration data successfully. After CONF_DONE goes high, send two additional falling edges on DCLK to begin initialization and enter user mode.
- (8) After the option bit to enable the <code>INIT_DONE</code> pin is configured into the device, the <code>INIT_DONE</code> goes low.

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Table 50 lists the timing parameters for Stratix V devices for FPP configuration when the DCLK-to-DATA[] ratio is 1.

Table 50. FPP Timing Parameters for Stratix V Devices (1)

| Symbol | Parameter | Minimum | Maximum | Units |
|------------------------|--|-------------------------|----------------------|-------|
| t _{CF2CD} | nCONFIG low to CONF_DONE low | _ | 600 | ns |
| t _{CF2ST0} | nconfig low to nstatus low | _ | 600 | ns |
| t _{CFG} | nCONFIG low pulse width | 2 | _ | μS |
| t _{STATUS} | nstatus low pulse width | 268 | 1,506 ⁽²⁾ | μ\$ |
| t _{CF2ST1} | nCONFIG high to nSTATUS high | _ | 1,506 ⁽³⁾ | μ\$ |
| t _{CF2CK} (6) | nCONFIG high to first rising edge on DCLK | 1,506 | _ | μ\$ |
| t _{ST2CK} (6) | nSTATUS high to first rising edge of DCLK | 2 | _ | μ\$ |
| t _{DSU} | DATA[] setup time before rising edge on DCLK | 5.5 | _ | ns |
| t _{DH} | DATA[] hold time after rising edge on DCLK | 0 | _ | ns |
| t _{CH} | DCLK high time | $0.45 \times 1/f_{MAX}$ | _ | S |
| t _{CL} | DCLK low time | $0.45 \times 1/f_{MAX}$ | _ | S |
| t _{CLK} | DCLK period | 1/f _{MAX} | _ | S |
| f _{MAX} | DCLK frequency (FPP ×8/×16) | _ | 125 | MHz |
| | DCLK frequency (FPP ×32) | _ | 100 | MHz |
| t _{CD2UM} | CONF_DONE high to user mode (4) | 175 | 437 | μS |
| t _{CD2CU} | CONF_DONE high to CLKUSR enabled | 4 × maximum | | |
| | | DCLK period | _ | _ |
| t _{CD2UMC} | CONF_DONE high to user mode with CLKUSR option on (8576) | | _ | _ |

Notes to Table 50:

- (1) Use these timing parameters when the decompression and design security features are disabled.
- (2) This value is applicable if you do not delay configuration by extending the nCONFIG or nSTATUS low pulse width.
- (3) This value is applicable if you do not delay configuration by externally holding the nstatus low.
- (4) The minimum and maximum numbers apply only if you chose the internal oscillator as the clock source for initializing the device.
- (5) To enable the CLKUSR pin as the initialization clock source and to obtain the maximum frequency specification on these pins, refer to the Initialization section of the "Configuration, Design Security, and Remote System Upgrades in Stratix V Devices" chapter.
- (6) If nSTATUS is monitored, follow the t_{ST2CK} specification. If nSTATUS is not monitored, follow the t_{CF2CK} specification.

FPP Configuration Timing when DCLK-to-DATA [] > 1

Figure 13 shows the timing waveform for FPP configuration when using a MAX II device, MAX V device, or microprocessor as an external host. This waveform shows timing when the DCLK-to-DATA [] ratio is more than 1.

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Table 51 lists the timing parameters for Stratix V devices for FPP configuration when the DCLK-to-DATA [] ratio is more than 1.

Table 51. FPP Timing Parameters for Stratix V Devices When the DCLK-to-DATA[] Ratio is >1 $^{(1)}$

| Symbol | Parameter | Minimum | Maximum | Units |
|------------------------|---|--------------------------------------|----------------------|-------|
| t _{CF2CD} | nconfig low to conf_done low | _ | 600 | ns |
| t _{CF2ST0} | nconfig low to nstatus low | _ | 600 | ns |
| t _{CFG} | nCONFIG low pulse width | 2 | _ | μS |
| t _{STATUS} | nstatus low pulse width | 268 | 1,506 ⁽²⁾ | μS |
| t _{CF2ST1} | nconfig high to nstatus high | _ | 1,506 ⁽²⁾ | μS |
| t _{CF2CK} (5) | nconfig high to first rising edge on DCLK | 1,506 | _ | μS |
| t _{ST2CK} (5) | nstatus high to first rising edge of DCLK | 2 | _ | μS |
| t _{DSU} | DATA[] setup time before rising edge on DCLK | 5.5 | _ | ns |
| t _{DH} | DATA[] hold time after rising edge on DCLK | N-1/f _{DCLK} ⁽⁵⁾ | _ | S |
| t _{CH} | DCLK high time | $0.45 \times 1/f_{MAX}$ | _ | S |
| t _{CL} | DCLK low time | $0.45 \times 1/f_{MAX}$ | _ | S |
| t _{CLK} | DCLK period | 1/f _{MAX} | _ | S |
| f _{MAX} | DCLK frequency (FPP ×8/×16) | _ | 125 | MHz |
| | DCLK frequency (FPP ×32) | _ | 100 | MHz |
| t _R | Input rise time | _ | 40 | ns |
| t _F | Input fall time | _ | 40 | ns |
| t _{CD2UM} | CONF_DONE high to user mode (3) | 175 | 437 | μS |
| t _{CD2CU} | CONF_DONE high to CLKUSR enabled 4 × maximum DCLK period — | | _ | _ |
| t _{CD2UMC} | CONF_DONE high to user mode with CLKUSR option on $ \begin{array}{c} t_{\text{CD2CU}} + \\ (8576 \times \text{CLKUSR} \\ \text{period})^{(4)} \end{array} $ | | _ | _ |

Notes to Table 51:

- (1) Use these timing parameters when you use the decompression and design security features.
- (2) You can obtain this value if you do not delay configuration by extending the nconfig or nstatus low pulse width.
- (3) The minimum and maximum numbers apply only if you use the internal oscillator as the clock source for initializing the device.
- (4) To enable the CLKUSR pin as the initialization clock source and to obtain the maximum frequency specification on these pins, refer to the Initialization section of the "Configuration, Design Security, and Remote System Upgrades in Stratix V Devices" chapter.
- (5) N is the DCLK-to-DATA ratio and f_{DCLK} is the DCLK frequency the system is operating.
- (6) If nstatus is monitored, follow the t_{status} specification. If nstatus is not monitored, follow the t_{cfack} specification.

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Table 60. Glossary (Part 2 of 4)

| Letter | Subject | Definitions | |
|------------------|-------------------------------|--|--|
| G | | | |
| Н | _ | - | |
| 1 | | | |
| J | JTAG Timing Specifications | High-speed I/O block—Deserialization factor (width of parallel data bus). JTAG Timing Specifications: TMS TDI TCK TJPSU TJ | |
| K L M N | _ | | |
| P | PLL Specifications | Diagram of PLL Specifications (1) CLKOUT Pins Four Core Clock Reconfigurable in User Mode External Feedback Note: (1) Core Clock can only be fed by dedicated clock input pins or PLL outputs. | |
| Q | _ | - | |
| R | R _L | Receiver differential input discrete resistor (external to the Stratix V device). | |
| | _ <u>-</u> | 1 | |

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Table 60. Glossary (Part 3 of 4)

| Letter | Subject | Definitions | | | | |
|--------|---|--|--|--|--|--|
| | SW (sampling window) | Timing Diagram—the period of time during which the data must be valid in order to capture it correctly. The setup and hold times determine the ideal strobe position within the sampling window, as shown: Bit Time 0.5 x TCCS RSKM Sampling Window (SW) 0.5 x TCCS | | | | |
| S | Single-ended voltage referenced I/O standard | The JEDEC standard for SSTL and HSTL I/O defines both the AC and DC input signal values. The AC values indicate the voltage levels at which the receiver must meet its timing specifications. The DC values indicate the voltage levels at which the final logic state of the receiver is unambiguously defined. After the receiver input has crossed the AC value, the receiver changes to the new logic state. The new logic state is then maintained as long as the input stays beyond the DC threshold. This approach is intended to provide predictable receiver timing in the presence of input waveform ringing: Single-Ended Voltage Referenced I/O Standard Voh Vih(DC) Voh Vih(DC) Voh Vih(DC) Voh Vik(AC) Voh Vik(AC) | | | | |
| | t _C | High-speed receiver and transmitter input and output clock period. | | | | |
| | TCCS (channel- to-channel-skew) | The timing difference between the fastest and slowest output edges, including t_{CO} variation and clock skew, across channels driven by the same PLL. The clock is included in the TCCS measurement (refer to the <i>Timing Diagram</i> figure under SW in this table). | | | | |
| | | High-speed I/O block—Duty cycle on the high-speed transmitter output clock. | | | | |
| T | t _{DUTY} | Timing Unit Interval (TUI) The timing budget allowed for skew, propagation delays, and the data sampling window. (TUI = $1/(\text{receiver input clock frequency multiplication factor}) = t_c/w)$ | | | | |
| | t _{FALL} | Signal high-to-low transition time (80-20%) Cycle-to-cycle jitter tolerance on the PLL clock input. | | | | |
| | t _{INCCJ} | | | | | |
| | t _{OUTPJ_IO} | Period jitter on the general purpose I/O driven by a PLL. | | | | |
| | t _{OUTPJ_DC} | Period jitter on the dedicated clock output driven by a PLL. | | | | |
| | t _{RISE} | Signal low-to-high transition time (20-80%) | | | | |
| U | _ | _ | | | | |

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